SN54ALS174, SN54ALS175, SN54AS174, SN54AS175A
SN74ALS174, SN74ALS175, SN74AS174, SN74AS175A
HEX/QUADRUPLE D-TYPE FLIP-FLOPS WITH CLEAR

SDAS207B – APRIL 1982 – REVISED DECEMBER 1994

- ′ALS174 and ′AS174 Contain Six Flip-Flops With Single-Rail Outputs
- ′ALS175 and ′AS175A Contain Four Flip-Flops With Double-Rail Outputs
- Buffered Clock and Direct-Clear Inputs
- Applications Include:
  - Buffer/Storage Registers
  - Shift Registers
  - Pattern Generators
- Fully Buffered Outputs for Maximum Isolation From External Disturbances (′AS Only)
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

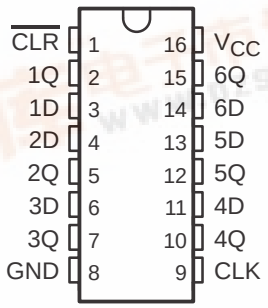
These positive-edge-triggered flip-flops utilize TTL circuitry to implement D-type flip-flop logic. All have a direct-clear ($\overline{CLR}$) input, and the ′ALS175 and ′AS175A feature complementary outputs from each flip-flop.

Information at the data (D) inputs meeting the setup-time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock (CLK) input is at either the high or low level, the D-input signal has no effect at the output.

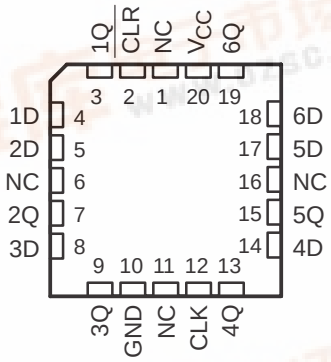
These circuits are fully compatible for use with most TTL circuits.

The SN54ALS174, SN54ALS175, SN54AS174, and SN54AS175A are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS174, SN74ALS175, SN74AS174, and SN74AS175A are characterized for operation from 0°C to 70°C.

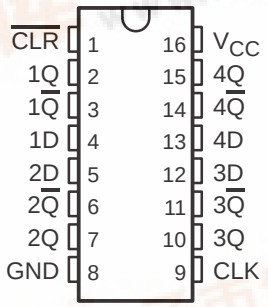
SN54ALS174, SN54AS174 . . . J PACKAGE
SN74ALS174, SN74AS174 . . . D OR N PACKAGE
(TOP VIEW)



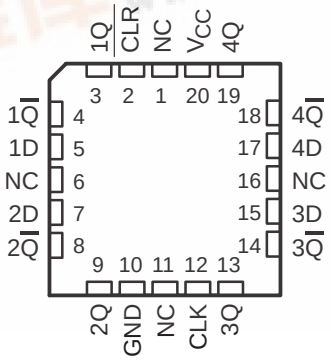
SN54ALS174, SN54AS174 . . . FK PACKAGE
(TOP VIEW)



SN54ALS175, SN54AS175A . . . J PACKAGE
SN74ALS175, SN74AS175A . . . D OR N PACKAGE
(TOP VIEW)



SN54ALS175, SN54AS175A . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

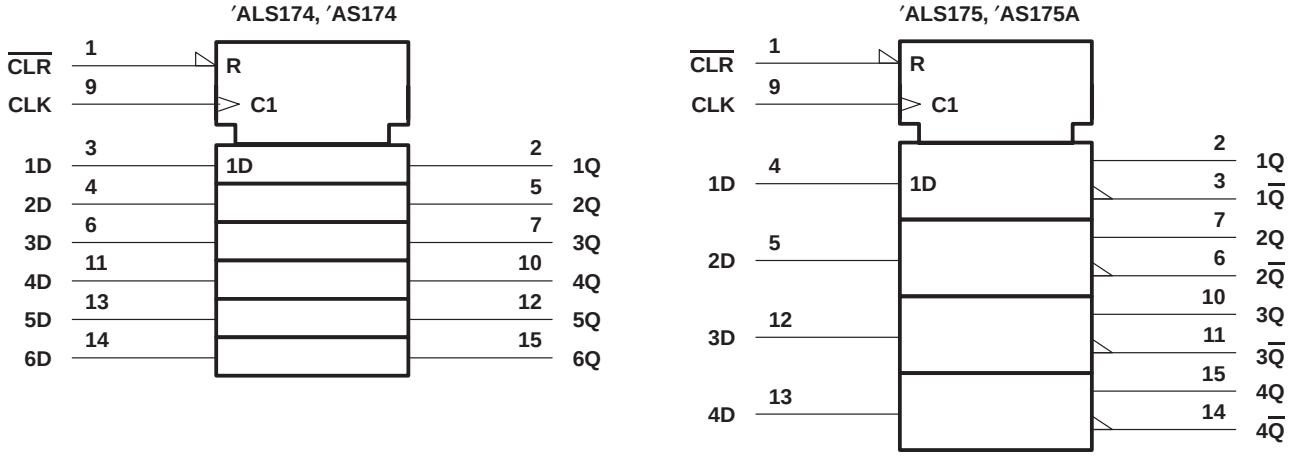
TEXAS INSTRUMENTS

FUNCTION TABLE
(each flip-flop)

INPUTS			OUTPUTS	
$\overline{CLR}$	CLK	D	Q	$\overline{Q}$†
L	X	X	L	H
H	↑	H	H	L
H	↑	L	L	H
H	L	X	Q_0	$\overline{Q}_0$

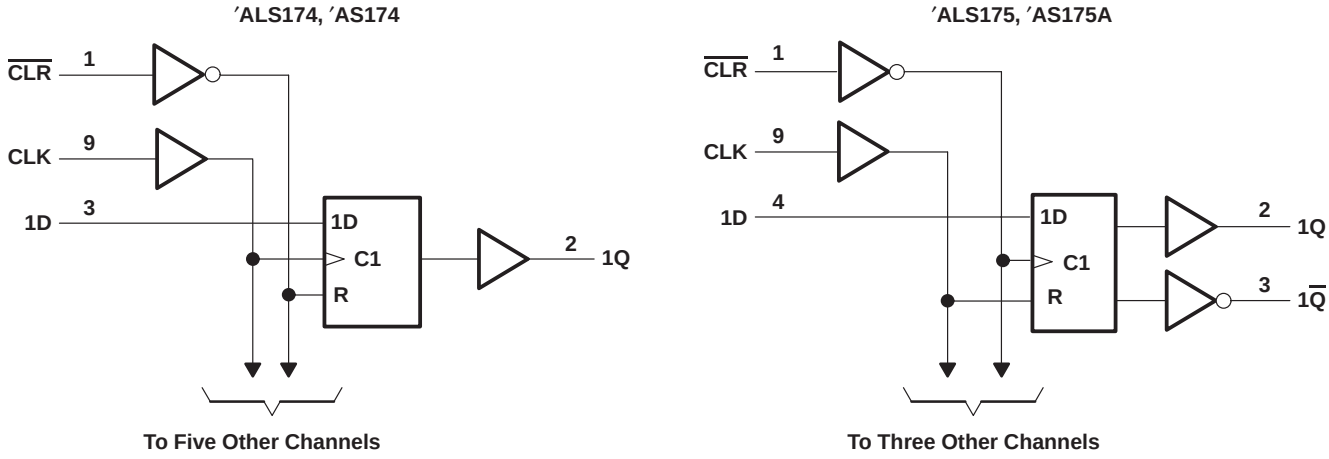
† ′ALS175 and ′AS175A only

logic symbols‡



‡ These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, J, and N packages.

logic diagrams (positive logic)



Pin numbers shown are for the D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V_{CC} . . . . . 7 V
Input voltage, V_I . . . . . 7 V
Operating free-air temperature range, T_A: SN54ALS174, SN54ALS175 . . . . . −55°C to 125°C
SN74ALS174, SN74ALS175 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN54ALS174 SN54ALS175			SN74ALS174 SN74ALS175			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
I_{OH}	High-level output current				−0.4			−0.4	mA
I_{OL}	Low-level output current				4			8	mA
f_{clock}	Clock frequency		0		40	0		50	MHz
t_w	Pulse duration	$\overline{CLR}$ low	15			10			ns
		CLK high	12.5			10			
		CLK low	12.5			10			
t_{su}	Setup time before CLK↑	Data	15			10			ns
		$\overline{CLR}$ inactive	8			6			
t_h	Hold time, data after CLK↑		0			0			ns
T_A	Operating free-air temperature		−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54ALS174 SN54ALS175			SN74ALS174 SN74ALS175			UNIT
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = −18 mA			−1.5			−1.5	V
V_{OH}		V_{CC} = 4.5 V to 5.5 V,	I_{OH} = −0.4 mA	V_{CC} −2			V_{CC} −2			V
V_{OL}		V_{CC} = 4.5 V	I_{OL} = 4 mA		0.25	0.4		0.25	0.4	V
			I_{OL} = 8 mA					0.35	0.5	
I_I		V_{CC} = 5.5 V,	V_I = 7 V			0.1			0.1	mA
I_{IH}		V_{CC} = 5.5 V,	V_I = 2.7 V			20			20	μA
I_{IL}	All others	V_{CC} = 5.5 V,	V_I = 0.4 V			−0.1			−0.1	mA
	CLK					−0.15				
I_O§		V_{CC} = 5.5 V,	V_O = 2.25 V	−20		−112	−30		−112	mA
I_{CC}	′ALS174	V_{CC} = 5.5 V,	See Note 1		11	19		11	19	mA
	′ALS175				8	14		9	14	

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.
NOTE 1: I_{CC} is measured with D inputs and $\overline{CLR}$ grounded, and CLK at 4.5 V.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN to MAX†				UNIT
			SN54ALS174 SN54ALS175		SN74ALS174 SN74ALS175		
			MIN	MAX	MIN	MAX	
f_{max}			40		50		MHz
t_{PLH}	$\overline{CLR}$	Any $\overline{Q}$ (′ALS175) Any Q	3	20	5	18	ns
t_{PHL}			5	30	8	23	
t_{PLH}	CLK	Any Q (or Q, ′ALS175)	3	20	3	15	ns
t_{PHL}			5	24	5	17	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V_{CC} . . . . . 7 V
Input voltage, V_I . . . . . 7 V
Operating free-air temperature range, T_A: SN54AS174, SN54AS175A . . . . . −55°C to 125°C
SN74AS174, SN74AS175A . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

				SN54AS174 SN54AS175A			SN74AS174 SN74AS175A			UNIT
				MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage			4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage			2			2			V
V_{IL}	Low-level input voltage					0.8			0.8	V
I_{OH}	High-level output current					−2			−2	mA
I_{OL}	Low-level output current					20			20	mA
f_{clock}*	Clock frequency			0		100	0		100	MHz
t_w*	Pulse duration	$\overline{CLR}$ low		5.5			5			ns
		CLK high		4			4			
		CLK low	′AS174	6			6			
			′AS175A	5			5			
t_{su}*	Setup time before CLK↑	Data	′AS174	4			4			ns
			′AS175A	3			3			
		$\overline{CLR}$ inactive		6			6			
t_h*	Hold time, data after CLK↑			1			1			ns
T_A	Operating free-air temperature			−55		125	0		70	°C

* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54AS174 SN54AS175A			SN74AS174 SN74AS175A			UNIT
				MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA			–1.2			–1.2	V
V_{OH}		V_{CC} = 4.5 V to 5.5 V,	I_{OH} = –2 mA	V_{CC} –2			V_{CC} –2			V
V_{OL}		V_{CC} = 4.5 V,	I_{OL} = 20 mA		0.35	0.5		0.35	0.5	V
I_I		V_{CC} = 5.5 V,	V_I = 7 V			0.1			0.1	mA
I_{IH}		V_{CC} = 5.5 V,	V_I = 2.7 V			20			20	µA
I_{IL}		V_{CC} = 5.5 V,	V_I = 0.4 V			–0.5			–0.5	mA
I_O‡		V_{CC} = 5.5 V,	V_O = 2.25 V	–30		–112	–30		–112	mA
I_{CC}	′AS174	V_{CC} = 5.5 V,	See Note 2		30	45		30	45	mA
	′AS175A				22.5	34		22.5	34	

† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.
NOTE 2: I_{CC} is measured with D inputs, $\overline{CLR}$, and CLK grounded.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN to MAX§				UNIT
			SN54AS174		SN74AS174		
			MIN	MAX	MIN	MAX	
f_{max}*			100		100		MHz
t_{PHL}	$\overline{CLR}$	Any Q	5	15	5	14	ns
t_{PLH}	CLK	Any Q	3.5	9.5	3.5	8	ns
t_{PHL}			4.5	11.5	4.5	10	

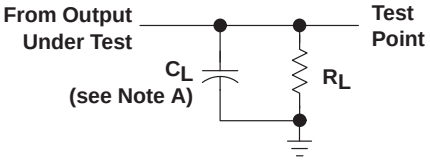
* On products compliant to MIL-STD-883, Class B, these parameters are based on characterization data but are not production tested.
§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics (see Figure 1)

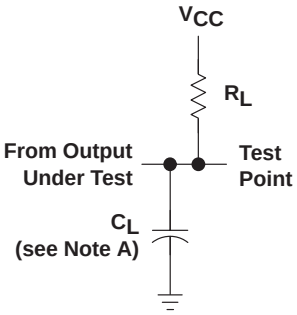
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω, T_A = MIN to MAX§				UNIT
			SN54AS175A		SN74AS175A		
			MIN	MAX	MIN	MAX	
f_{max}*			100		100		MHz
t_{PLH}	$\overline{CLR}$	Any Q or $\overline{Q}$	4	10	4	9	ns
t_{PHL}			4.5	15	4.5	13	
t_{PLH}	CLK	Any Q or $\overline{Q}$	4	8.5	4	7.5	ns
t_{PHL}			4	11	4	10	

* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.
§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

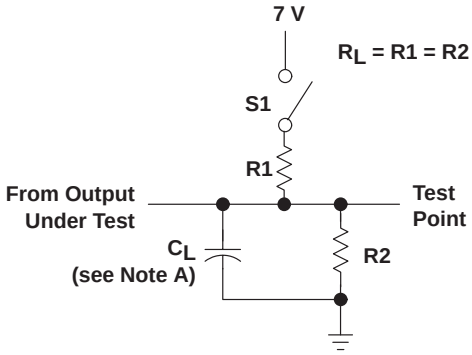
PARAMETER MEASUREMENT INFORMATION
SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



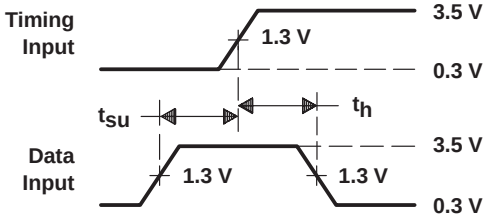
LOAD CIRCUIT FOR
BI-STATE
TOTEM-POLE OUTPUTS



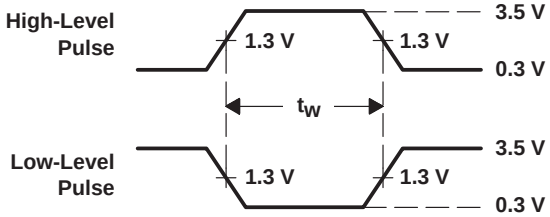
LOAD CIRCUIT
FOR OPEN-COLLECTOR OUTPUTS



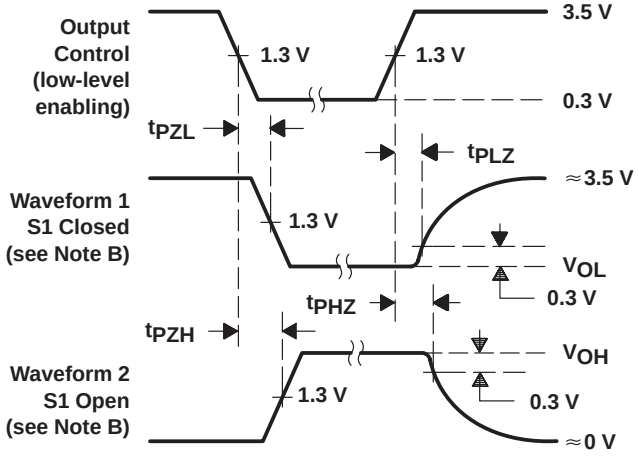
LOAD CIRCUIT
FOR 3-STATE OUTPUTS



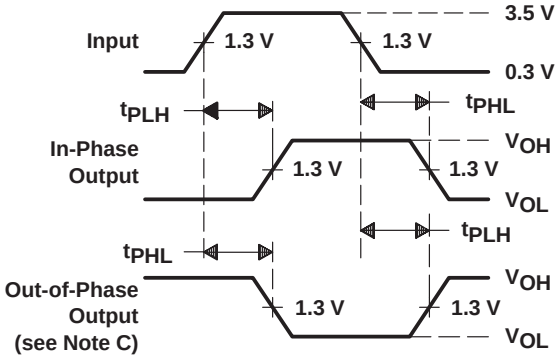
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATIONS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
D. All input pulses have the following characteristics: PRR ≤ 1 MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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